

Member State of OIML Japan



OIML Certificate No R76/1992-TP1-05.02

## OIML CERTIFICATE OF CONFORMITY

**Issuing authority** 

Name:

National Institute of Advanced Industrial Science and Technology

Address:

1-3-1, Kasumigaseki, Chiyoda-ku, TOKYO, 100-8921, Japan

Person responsible: Hiroyuki Yoshikawa

**Applicant** 

Name:

A&D Company, Limited

Address:

3-23-14 Higashi-ikebukuro, Toshima-ku, Tokyo 170-0013, JAPAN

Manufacturer of the certified pattern

Name:

A&D SCALES CO.,LTD.

Address:

162-4 INSAN-NI, DEOGSAN-MYEON, JINCHEON-GUN,

CHUNGCHEONGBUG-DO, KOREA

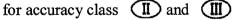
Identification of the certified pattern:

Type EK-i(K)

Further characteristics see page 2

This certificate attests the conformity of the above-mentioned pattern (represented by the samples identified in the associated test report) with the requirements of the following Recommendation(s) of the International Organization of Legal Metrology (OIML):

**R76-1**, edition 1992, including amendment (1994),



This certificate relates only to the metrological and technical characteristics of the pattern of the instrument concerned, as covered by the relevant OIML International Recommendation(s).

This certificate does not bestow any form of legal international approval.



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OIML Certificate No R76/1992-JP1-05.02

The conformity was established by tests described in the associated test report N° 05-02-A/R76 (53 pages) and N° 05-02-B/R76 (25 pages).

The Issuing Authority

The CIML member

Dr. H. Yoshikawa

Dr. Y. Miki

President

Dec 26 2005

Dec 26 2005

## Characteristics:

Туре	EK-i (K)	
Accuracy class	(II)	
Max	600 g∼6000 g	. 400 g∼6000 g
e ≧	0.1 g or 1 g	0.1 g or 1 g
d ≧	0.01 g or 0.1 g	0.01g or 0.1 g
n	≤ 6000	≤ 6000
Min	0.5 g or 5 g	0.2 g or 2 g
Tare-balancing	100% of Max	
range		
Temperature	5 °C / 35 °C	
range		

Important note: Apart from the mention of certificate's reference number and the name of the OIML Member State in which the certificate was issued, partial quotation of the certificate or of the associated test report is not permitted, though they may be reproduced in full.